



1-24-03

RCE  
#2807  
#11  
#23103

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application No.: 09/778,245 Confirmation No.: 9085  
First Named Inventor: SHING LEE ET AL. Filing Date: February 6, 2001  
Group Art Unit: 2877 Examiner: Hoa O. Pham  
Atty. Docket No.: M-10685-1C US  
Title: SYSTEM FOR MEASURING POLARIMETRIC SPECTRUM AND OTHER PROPERTIES OF A SAMPLE  
Assignee: KLA-TENCOR CORPORATION

Match and Return

San Francisco, California  
January 22, 2003

BOX RCE  
COMMISSIONER FOR PATENTS  
Washington, D. C. 20231

**REQUEST FOR CONTINUED EXAMINATION (RCE)**

Dear Sir:

This is a Request under 37 C.F.R. § 1.114 for Continued Examination of the above-identified application.

Please consider the Supplemental Information Disclosure Statement, which are enclosed/were previously submitted.

The Commissioner is hereby authorized to charge the RCE fee of \$750.00, required under 37 C.F.R. § 1.17(e), to Deposit Account No. 19-2386. The Commissioner is also authorized to charge any other fees which may be required. A duplicate copy of this sheet is attached.

Please contact the undersigned attorney at (415) 217-6000 with any questions concerning this request or the above-identified patent application.

LAW OFFICES OF  
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San Jose, CA  
San Francisco, CA

01/27/2003 MBLANC 00000006 192386 09778245  
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#913569 v1 - M-10685-1C US - RCE application

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Application No. 09/778,245

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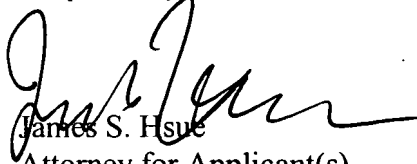
JAN 28 2003

TECHNOLOGY CENTER 2806

EXPRESS MAIL LABEL NO:

EV 259161167 US

Respectfully submitted,



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